

PATENT
450100-05032**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Mitsutoshi SHINKAI et al.

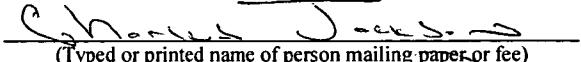
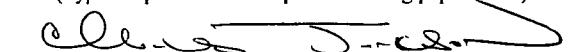
International Application No.: PCT/JP2004/004717

International Filing Date: March 31, 2004

For: RECORDING APPARATUS AND METHOD

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Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP2004/004717. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

10/516706
TOS 670621
DTIZ Rec'd PCT/PTO 02 DEC 2004
PATENT
450100-05032

REMARKS

Entry of this Information Disclosure Statement and an early examination on the
merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

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Enclosures

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Sheet 1 of 1

Based on Form PTO-1449 (3/90) LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 450100-05032	SERIAL NO. 10/516706 Filed Concurrently Herewith
	APPLICANT Mitsutoshi SHINKAI et al.	
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U.S. PATENT DOCUMENTS							
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FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/DH/	AL	JP 2003-18549	01/17/03	Japan	=====	=====	
/DH/	AM	JP 2000-11545	01/14/00	Japan	=====	=====	
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